



## Certificate of Accreditation: Supplement

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Accreditation is granted to the facility to perform the following testing:

FIELD OF TEST	ITEMS, MATERIALS OR PRODUCTS TESTED	SPECIFIC TESTS OR PROPERTIES MEASURED	SPECIFICATION, STANDARD METHOD OR TECHNIQUE USED	RANGE (WHERE APPROPRIATE) AND GOVERNMENT ORDINANCE STANDARD VALUE
Electrical <sup>F</sup>	Semiconductor device	Temperature setting in the chamber of Burn-In Machine	Procedures for High Temperature Operating Life Test (SBS21019) On the basis of: JESD22-A108-4.2.3.2 Standard  Temperature data collection system Thermograph	125 °C ± 3 °C
		Voltage setting of Burn-In Machine	Multi-meter R6452A	1.6 V ± 0.3 V 3.7 V ± 0.3 V

1. The presence of a superscript F means that the laboratory performs testing of the indicated parameter at its fixed location. Example: Outside Micrometer <sup>F</sup> would mean that the laboratory performs this testing at its fixed location.